

Bias-temperature stability test for metal-oxide, semiconductor, field-effect transistors (MOSFET)

The European Standard EN 62373:2006 has the status of a British Standard

ICS 31.080

National foreword

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The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on EPL/47 can be obtained on request to its secretary.

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